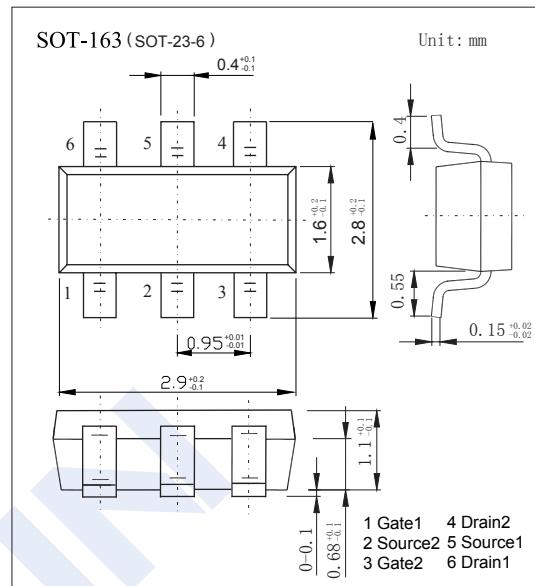
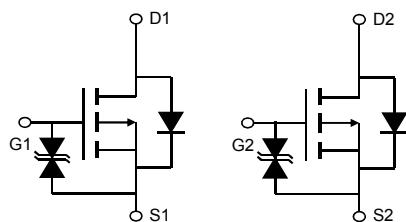


Dual P-Channel MOSFET

AO6801E (KO6801E)

■ Features

- V_{DS} (V) = -30V
- I_D = -2A (V_{GS} = -10V)
- $R_{DS(ON)} < 110\text{m}\Omega$ (V_{GS} = -10V)
- $R_{DS(ON)} < 135\text{m}\Omega$ (V_{GS} = -4.5V)
- $R_{DS(ON)} < 185\text{m}\Omega$ (V_{GS} = -2.5V)
- ESD Rating: 2000V HBM



■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 12	
Continuous Drain Current	I_D	-2	A
		-1.6	
Pulsed Drain Current	I_{DM}	-15	
Power Dissipation	P_D	0.7	W
		0.45	
Thermal Resistance.Junction- to-Ambient	R_{thJA}	180	$^\circ\text{C}/\text{W}$
		230	
Thermal Resistance.Junction- to-Lead	R_{thJL}	180	
Junction Temperature	T_J	150	
Junction Storage Temperature Range	T_{stg}	-55 to 150	$^\circ\text{C}$

Dual P-Channel MOSFET

AO6801E (KO6801E)

■ Electrical Characteristics $T_a = 25^\circ C$

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DSS}	$I_D=-250 \mu A, V_{GS}=0V$	-30			V
Gate-Source breakdown voltage	BV_{GSO}	$V_{DS}=0V, I_G=\pm 250 \mu A$	± 12			
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=-30V, V_{GS}=0V$			-1	uA
		$V_{DS}=-30V, V_{GS}=0V, T_J=55^\circ C$			-5	
Gate-Body leakage current	I_{GSS}	$V_{DS}=0V, V_{GS}=\pm 12V$			± 10	uA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_D=-250 \mu A$	-0.7		-1.5	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS}=-10V, I_D=-2A$			110	mΩ
		$V_{GS}=-10V, I_D=-2A, T_J=125^\circ C$			158	
		$V_{GS}=-4.5V, I_D=-1.5A$			135	
		$V_{GS}=-2.5V, I_D=-1A$			185	
On state drain current	$I_{D(on)}$	$V_{GS}=-10V, V_{DS}=-5V$	-15			A
Forward Transconductance	g_{FS}	$V_{DS}=-5V, I_D=-2A$		7		S
Input Capacitance	C_{iss}	$V_{GS}=0V, V_{DS}=-15V, f=1MHz$		305		pF
Output Capacitance	C_{oss}			42		
Reverse Transfer Capacitance	C_{rss}			26		
Gate resistance	R_g	$V_{GS}=0V, V_{DS}=0V, f=1MHz$		8.5	17	Ω
Total Gate Charge (10V)	Q_g	$V_{GS}=-10V, V_{DS}=-15V, I_D=-2A$		7	12	nC
Total Gate Charge (4.5V)				3.5	6	
Gate Source Charge	Q_{gs}	$V_{GS}=-10V, V_{DS}=-15V, I_D=-2A$		0.7		nC
Gate Drain Charge	Q_{gd}			1.2		
Turn-On Delay Time	$t_{d(on)}$	$V_{GS}=-10V, V_{DS}=-15V, R_L=7.5\Omega, R_{GEN}=3\Omega$		6		ns
Turn-On Rise Time	t_r			4		
Turn-Off Delay Time	$t_{d(off)}$			23		
Turn-Off Fall Time	t_f			7		
Body Diode Reverse Recovery Time	t_{rr}	$I_F=-2A, dI/dt=500A/\mu s$		9.5		nC
Body Diode Reverse Recovery Charge	Q_{rr}			13.5		
Maximum Body-Diode Continuous Current	I_s				-1	A
Diode Forward Voltage	V_{SD}	$I_s=-1A, V_{GS}=0V$			-1	V

* The static characteristics in Figures 1 to 6 are obtained using <300us pulses, duty cycle 0.5% max.

■ Marking

Marking	V1**
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Dual P-Channel MOSFET

AO6801E (KO6801E)

■ Typical Characteristics

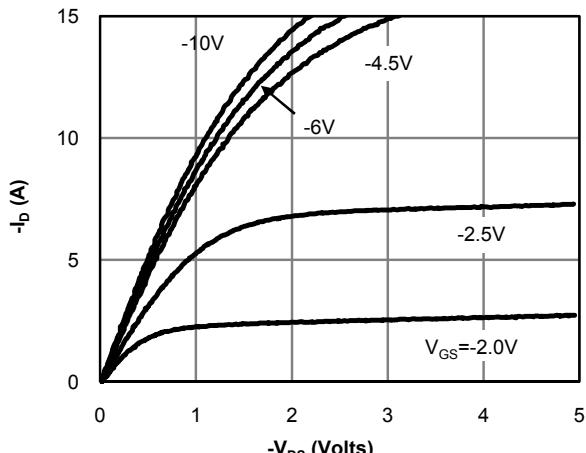


Fig 1: On-Region Characteristics (Note E)

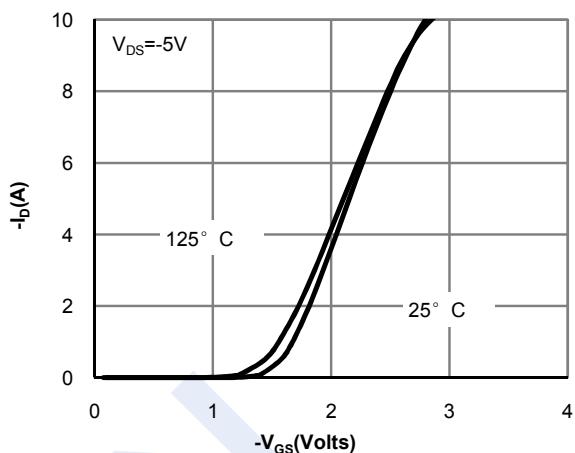


Figure 2: Transfer Characteristics (Note E)

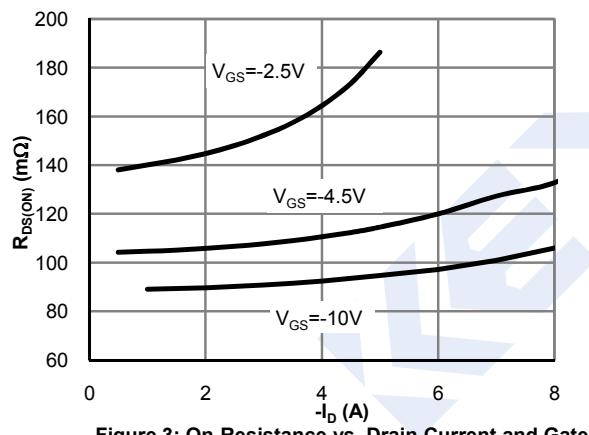


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

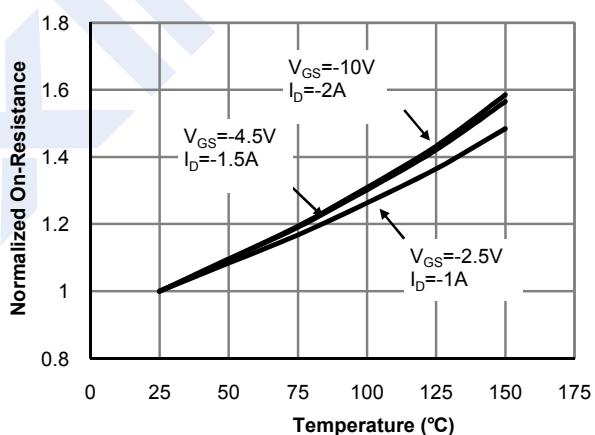


Figure 4: On-Resistance vs. Junction Temperature (Note E)

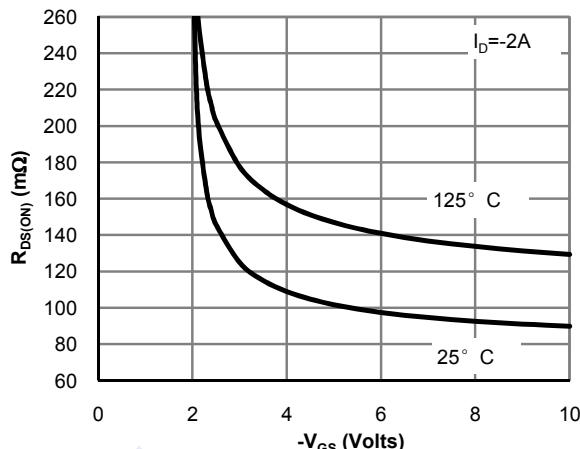


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

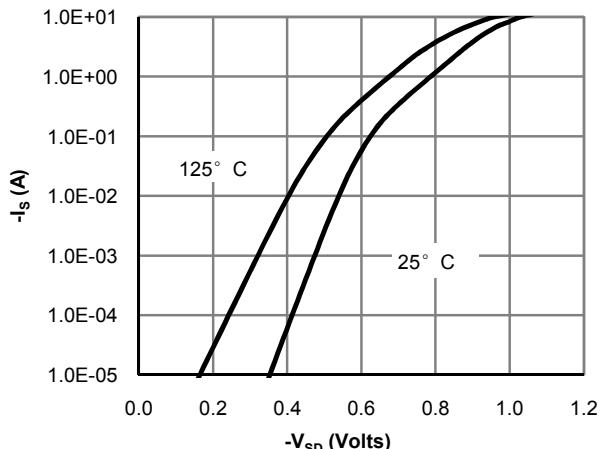


Figure 6: Body-Diode Characteristics (Note E)

Dual P-Channel MOSFET

AO6801E (KO6801E)

■ Typical Characteristics

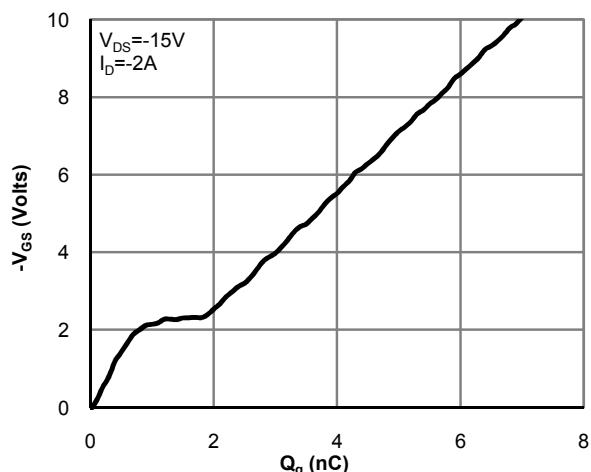


Figure 7: Gate-Charge Characteristics

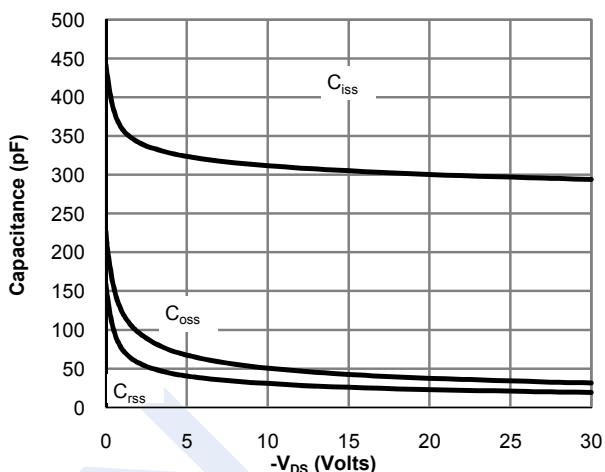


Figure 8: Capacitance Characteristics

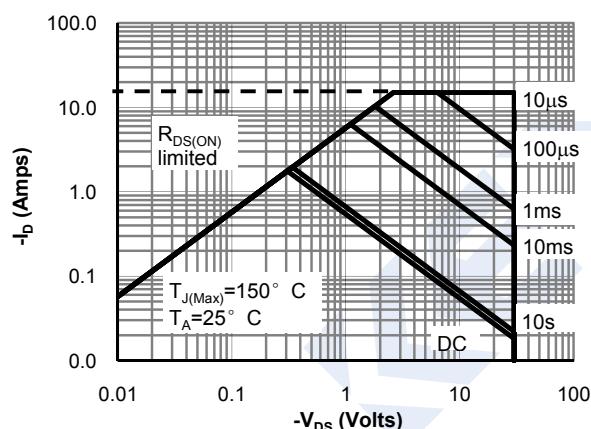


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

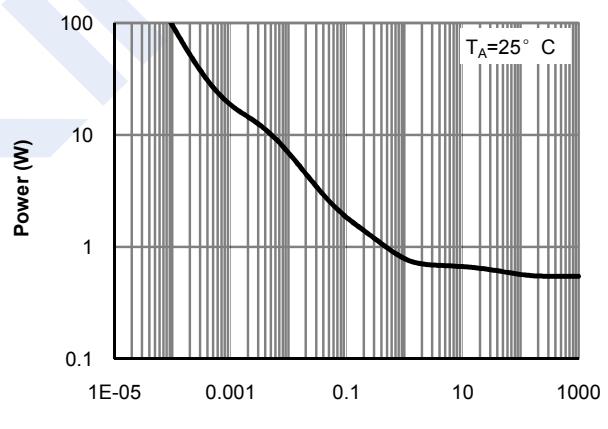


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note F)

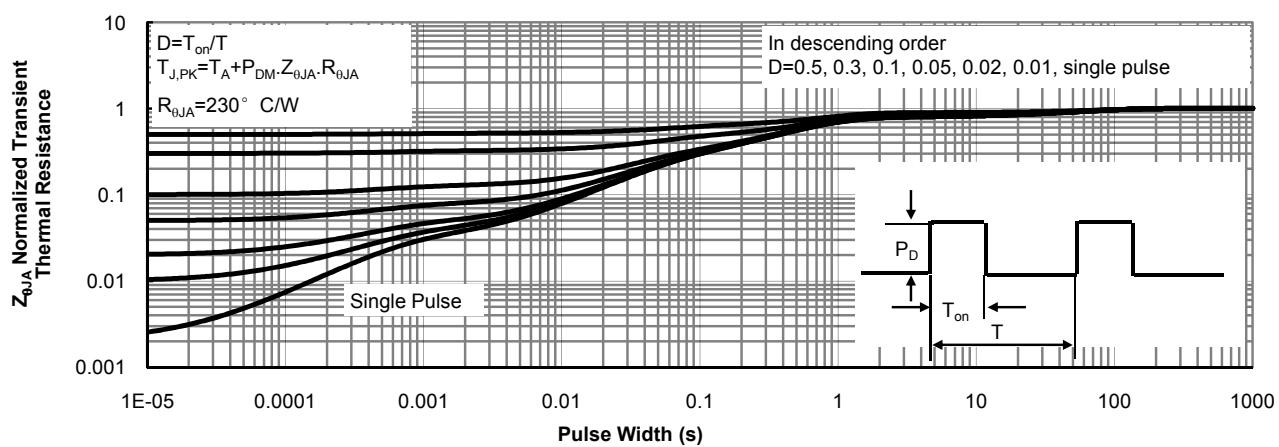


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)